

Search Notes

Application/Control No.

10/717,305

Examiner

CHAN S. PARK

Applicant(s)/Patent under
Reexamination

IMAI ET AL.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
358	1.12,1.18, 1.9,453	7/27/2007	CP
358	452	7/27/2007	CP
382	282	7/27/2007	CP

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East (see the search history)	7/27/2007	CP